NSN 6625-01-391-4404

Fiig: T228-a

Semiconductor Device Test Set - Page 1 of 1



View Online at https://aerobasegroup.com/nsn/6625-01-391-4404 Width: 9.000 inches Depth: 11.000 inches **End Application:** Gpete program **Test Type For Which Designed:** Test signal frequency **Criticality Code Justification:** Feat **Special Features:** Items are being coded as critical to insure source inspection will be performed at the point of manufacture, prior to material receipt by the us navy or other dod components. These items are piece parts or end items in support of vital military hardware necessary to sustain the successful mission of the ships, submarines, and shore stations of the us navy. Critical features including, but not limited to, dimensions, tolerances/clearances, electronic characteristics, and metallurgical properties will bespecified for government q ar (quality assurance representatives) to insure the highest possible degree of quality and reliability of these parts being delivered under navicp contracts Height: 4.000 inches Shelf Life: N/a **Unit Of Measure: Demilitarization:** No